

*SUB  
C1*

What is claimed is:

1 1. A capacitor comprising:  
2 a plurality of conductive layers embedded in a dielectric; and  
3 a plurality of vias coupling at least two of the plurality of conductive layers to a  
4 plurality of connection sites.

1 2. The capacitor of claim 1, wherein the capacitor has a thickness of between about  
2 .5 millimeter and about 1 millimeter.

1 3. The capacitor of claim 2, wherein the capacitor has a capacitance of between  
2 about 20 and about 30 microfarads.

1 4. The capacitor of claim 1, wherein the plurality of controlled collapse chip  
2 connection sites have a pitch of between about 100 and about 500 microns.

1 5. The capacitor of claim 1, wherein the plurality of vias are plated through holes.

1 6. A capacitor comprising:  
2 a plurality of first conductive layers;  
3 a plurality of second conductive layers interlaced with the plurality of first  
4 conductive layers;  
5 a number of surfaces having a plurality of connection sites operable for coupling  
6 the capacitor to a substrate using a controlled collapse chip connection (C4); and  
7 a plurality of vias coupling the plurality of first conductive layers and the plurality  
8 of second conductive layers to at least two of the plurality of connection sites.

1 7. The capacitor of claim 6, wherein each of the plurality of first conductive layers is  
2 fabricated from a tungsten paste.

- Sub C1*
- 1 8. The capacitor of claim 6, wherein the number of surfaces is two.
- Sub B3*
- 1 9. A capacitor comprising:  
2 a multilayered capacitor having a number of outer surfaces; and  
3 a number of pads located on at least two of the number of outer surfaces wherein  
4 at least two of the number of pads are capable of being coupled to a substrate using a  
5 solder bump.
- Sub C1*
- 1 10. The capacitor of claim 9, wherein the multilayered capacitor includes a number of  
2 parallel conductive layers and the number of pads are coupled to the number of parallel  
3 conductive layers through vias.
- 1 11. The capacitor of claim 10, wherein the number of conductive layers is greater than  
2 about 50.
- 1 12. The capacitor of claim 11, wherein the number of pads is greater than about 4000.
- 1 13. A system comprising:  
2 a die including an electronic system;  
3 a capacitor located less than about .1 millimeter from the die and coupled to the  
4 die, the capacitor is capable of decoupling a power supply connection at the die without  
5 additional capacitors located external to the die; and  
6 a dielectric layer located between the capacitor and the die.
- 1 14. The system of claim 13, wherein the dielectric layer has a thickness of between  
2 about .05 millimeters and about .1 millimeters.
- 1 15. A system comprising:  
2 a first die;  
3 a second die; and

4 a capacitor having a first surface having a controlled collapse chip connection  
5 coupled to the first die and a second surface having a controlled collapse chip connection  
6 coupled to the second die.

1 16. The system of claim 15, wherein the first die includes a processor and the second  
2 die includes a communication system.

1 17. A system comprising:  
2 a substrate having a surface; and  
3 a capacitor having a plurality of vias coupled to a plurality of conductive layers in  
4 the capacitor, the capacitor is coupled to the surface at a plurality of connection sites.

1 18. A system comprising:  
2 a substrate having a first surface and a second surface;  
3 a die coupled to the first surface; and  
4 a capacitor having a plurality of vias coupled to a plurality of conductive layers in  
5 the capacitor, the capacitor is coupled to the second surface by a controlled collapse chip  
6 connection and the capacitor is electrically coupled to the die through the substrate.

1 19. The system of claim 18, wherein the die includes a processor.

1 20. The system of claim 19, wherein the die has a die surface and the capacitor has a  
2 capacitor surface and the capacitor surface is located less than about .1 millimeter from  
3 the die surface.

1 21. A system comprising:  
2 a processor requiring at least 5 watts of power to be operable; and  
3 a single multilayered single package capacitor coupled to the processor and  
4 capable of decoupling a power supply from the processor.

- 1       22.     The system of claim 21, wherein the single multilayered single package capacitor  
2     is capable of being mounted on a substrate by a plurality of solder bumps.
- 1       23.     The system of claim 22, wherein the single multilayered capacitor is capable of  
2     being mounted on a substrate using a controlled collapse chip connection.
- 1       24.     A method comprising:  
2              forming a stack of a plurality of screen printed dielectric sheets;  
3              forming a plurality of via holes in the stack;  
4              filling at least two of the plurality of via holes with a metal slurry; and  
5              co-firing the stack to form a capacitor.
- 1       25.     The method of claim 24, further comprising:  
2              coupling the stack to a substrate using a controlled collapse chip connection.
- 1       26.     The method of claim 24, further comprising:  
2              coupling a die to the substrate and to the capacitor.
- 1       27.     A method comprising:  
2              forming a capacitor having a plurality of conductive layers and a surface; and  
3              forming a pattern of pads on the surface, at least one pad in the pattern of pads is  
4              capable of being coupled to at least one of the plurality of conductive layers and capable  
5              of being coupled to a substrate using a solder bump attachment.
- 1       28.     The method of claim 27, further comprising:  
2              coupling the capacitor to a ceramic substrate using a solder bump attachment.
- 1       29.     A method comprising:  
2              selecting a substrate having a controlled collapse chip connection capability; and

- 3        mounting a multilayered capacitor on the substrate using the controlled collapse  
4        chip connection capability.
- (Handwritten note: Hold ELV)*

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